

<b>Notice of References Cited</b>	Application/Control No. <b>09/700,031</b>	Applicant(s)/Patent Under Reexam <b>Iwamoto et al.</b>	
	Examiner <b>John Kim</b>	Art Unit <b>1723</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	4,028,250	6/1977	Loft	210	259
B	4,872,990	10/1989	Van Wijk	210	644
C	5,266,195	11/1993	Hopkins	210	321.74
D	4,022,692	5/1977	Janneck	210	494
E	4,834,881	5/1989	Sawada et al.	210	321.74
F	4,253,962	3/1981	Thompson	210	414
G					
H					
I					
J					
K					
L					
M					

**FOREIGN PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
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**NON-PATENT DOCUMENTS**

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<sup>1</sup> Dates in MM-YYYY format are publication dates.

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